

Notice of References Cited	Application/Control No. 10/065,365	Applicant(s)/Patent Under Reexamination BASSETT ET AL.	
	Examiner Cynthia Britt	Art Unit 2133	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,658,613	12-2003	Rearick et al.	714/724
	C	US-6,556,938	04-2003	Rohrbaugh et al.	702/117
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	0388790	09-1990	EP	Littlebury	G01R/ 31/28
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NON-PATENT DOCUMENTS

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	U	"A Study of the Optimization of DC Parametric Tests" Chang, J.M. International Test Conference 1990 Proceedings: 10-14 Sept. 1990 pages 478 - 487 Inspec Accession Number: 3976214
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.